

Search Notes**Application/Control No.**

10/757,782

Examiner

José V. Chen

Applicant(s)/Patent under Reexamination

WUNSH ET AL.

Art Unit

3637

SEARCHED

Class	Subclass	Date	Examiner
108	25 24 27	9/14/15	JLC
	12		
	14		
	13		
	90		
	161		
206	769		
	770		
	326		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Tan & Base Gr. For Port-Art	9/20/15	JL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner